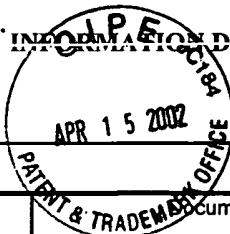
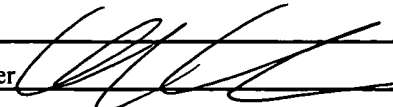


Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0756-2296		Serial No. 09/837,877	
INFORMATION DISCLOSURE STATEMENT 				Applicants: Shunpei YAMAZAKI et al.			
				Filing Date: April 19, 2001		Group Art Unit: N/A	
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No	
ML	11-354802	12/24/1999	JP			Full Eng	
<p>RECEIVED APR 18 2002 TECHNOLOGY CENTER 2800</p>							
Examiner 				Date Considered 7/26/02			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449  
(Rev. 8-83)Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-2

Serial No. 09/837,877

## INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 19, 2001

Group Art Unit: Not  
Assigned

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
ML	4,609,930	09/02/1986	Yamazaki			
ML	4,748,485	05/31/1988	Vasudev			
ML	4,977,105	12/11/1990	Okamoto et al.			
ML	4,984,033	01/08/1991	Ishizu et al.			
ML	4,996,575	02/26/1991	Ipri et al.			
ML	5,034,788	07/23/1991	Kerr			
ML	5,103,277	04/07/1992	Caviglia et al.			
ML	5,124,769	06/23/1992	Tanaka et al.			
ML	5,140,391	08/18/1992	Hayashi et al.			
ML	5,185,535	02/09/1993	Farb et al.			
ML	5,198,379	03/30/1993	Adan			
ML	5,233,211	08/03/1993	Hayashi et al.			
ML	5,246,882	09/21/1993	Hartmann			
ML	5,273,921	12/28/1993	Neudeck et al.			
	5,275,972	01/04/1994	Ogawa et al.			
	5,281,840	01/25/1994	Sarma			
	5,294,821	03/15/1994	Iwamatsu			
	5,327,001	07/05/1994	Wakai et al.			
	5,359,219	10/25/1994	Hwang			
	5,371,398	12/06/1994	Nishihara			
	5,420,048	05/30/1995	Kondo			
	5,470,793	11/28/1995	Kalnitsky			
	5,475,238	12/12/1995	Hamada			
	5,506,436	04/09/1996	Hayashi et al.			
	5,580,802	12/03/1996	Mayer et al.			
	5,604,368	02/18/1997	Taur et al.			
	5,807,772	09/15/1998	Takemura			
	5,818,076	10/06/1998	Zhang et al.			
	5,917,221	06/29/1999	Takemura			
ML	6,054,734	04/25/2000	Aozasa et al.			

Examiner

Date Considered

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

08/13/2001

Form PTO-1449  
(Rev. 8-83)Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-2

Serial No. 09/837,877

## INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 19, 2001

Group Art Unit: Not  
Assigned

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	6,252,248	06/26/2001	Sano et al.			

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
ML	0 178 447	04/23/1986	EP			Full Eng
	02-015676	01/19/1990	JP			Eng Abst
	02-666293	06/27/1997	JP			Full Eng
	03-082171	04/08/1991	JP			Eng Abst
	03-256365	11/15/1991	JP			Eng Abst
	04-152574	05/26/1992	JP			Eng Abst
	04-364074	12/16/1992	JP			Eng Abst
	11-354802	12/24/1999	JP			Eng Abst
	2000-183356	06/30/2000	JP			Full Eng
	2000-194014	07/14/2000	JP			Full Eng
	2000-196093	07/14/2000	JP			Full Eng
	57-032641	02/22/1982	JP			Eng Abst
	58-115850	07/09/1983	JP			Full Eng
	60-081869	05/09/1985	JP			Eng Abst
	60-154660	08/14/1985	JP			Eng Abst
	61-067269	04/07/1986	JP			Eng Abst
	61-088565	05/06/1986	JP			Eng Abst
	61-220371	09/30/1986	JP			Eng Abst
	62-005661	01/12/1987	JP			Eng Abst
	62-117359	05/28/1987	JP			Full Eng
	64-019761	01/23/1989	JP			Eng Abst
	64-053459	03/01/1989	JP			Full Eng
	64-053460	03/01/1989	JP			Full Eng
	64-059866	03/07/1989	JP			Full Eng
ML	93/21659	10/28/1993	WO			Full Eng

Examiner

Date Considered

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

08/13/2001

Form PTO-1449  
(Rev. 8-83)Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-2

Serial No. 09/837,877

## INFORMATIONAL DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 19, 2001

Group Art Unit: Not  
Assigned

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial	
ML	Farrah et al., "Analysis of Double-Gate Thin-Film Transistor", pp. 69-74, February 1967, IEEE Transactions on Electron Devices, Vol. ED-14, No. 2
	Ishii et al., "A Trial Product of Dual-Gate MOS (X MOS) Device", pp. 405, 1985, 46th Japan Society of Applied Physics, 2a-V-9
	Ishii et al., "Experimental Fabrication of XMOS Transistors Using Lateral Solid-Phase Epitaxy of CVD Silicon Films", pp. L521-L523, April 1990, Japanese Journal of Applied Physics, Vol. 29, No. 4
	Noguchi et al., "Advanced High Mobility Polysilicon Super-thin Film Transistor (SFT) Using Solid Phase Growth", pp. 549-552, 1986, Extended Abstracts of the 18th International Conference on Solid State Devices and Materials, Tokyo, B-10-2
	Hayashi et al., "Polysilicon Super-Thin-Film Transistor (SFT)", pp. L819-L820, November 1984, Japanese Journal of Applied Physics, Vol. 23, No. 11
	Hayashi et al., "High Performance Superthin Film Transistor (SFT) with Twin Gates", pp. 59-62, 1987, Extended Abstracts of the 19th Conference on Solid State Devices and Materials, Tokyo, A-3-5
	Sekigawa et al., "The Development of XMOS Transistor", pp. 44-49, 1986, Semiconductor World
	Tuan et al., "Dual-Gate a-Si:H Thin Film Transistors", pp. 357-359, December 1982, IEEE Electron Device Letters, Vol. EDL-3, No. 12
↓	Specifications and Drawings for Patent Application Serial No. 09/837,552, "Semiconductor Device and Manufacturing Method Thereof", Filing Date: April 19, 2001, Hishashi OHTANI et al.
ML	Specifications and Drawings for Patent Application Serial No. 09/837,558, "Semiconductor Device and Manufacturing Method Thereof", Filing Date: April 19, 2001, Shunpei YAMAZAKI et al.

Examiner

Date Considered

7/26/02

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

08/13/2001